

Designation:

**Date of Measurement:** 

## 2D X-Ray Diffraction Lab, Central Research Facility Indian Institute of Technology Kharagpur – 721302

| Requisition Number: Slot Schedule: |                                     |                          | Date of submission:  |   |               |  |
|------------------------------------|-------------------------------------|--------------------------|--|---|---------------|--|
|                                    |                                     |                          | Da   | ite:  |               | Time:  |
| 1)<br>2)<br>3)                     | Moisture; and/or<br>The sample comp | these so                 | completely and pro<br>substances must n<br>and how it is prep<br>out sample history  | ot be evolved du<br>pared must posit            | iring t       | the test<br>be mentioned in section 2.                                       |
| I. User's                          | Profile:                            |                          |  |   |               |  |
|                                    | ·                                   |                          | ng:  |   |               |  |
|                                    |                                     |                          |  |   |               |  |
| Mobile I                           | Phone No.:                          |                          |  |   |               |  |
| Tentativ                           | e title of the Thes                 | sis / Pro                | ject:  |   |               |  |
| Name a                             | nd email of the G                   | uide/Su                  | pervisor:  |   |               |  |
| II. Samp                           | le composition: _                   |                          |  |   |               |  |
| radioactiv<br>cancelled            | e substances and mo                 | oisture; a               |  | es must not be evolu                            | ved du        | ontain volatile, corrosive, toxic and ring the test. Provided slots will by. |
| Sl No.                             | Nature of test                      |                          | Slot duration  | No. of slots needed No. of samples to be tested |               |  |
| 1                                  | Phase Scan                          | 1 hr. (2 slots) 4samples |  |   |               |  |
| 2                                  | GI XRD                              | 1 hr. (2 slots) 2samples |  |   |               |  |
| 3                                  | Stress Analysis                     | 2 hr. (4 slots)2 samples |  |   |               |  |
| 4                                  | Texture                             | 2 hr. (                  | 4 slots) 1 sample  |   |               |  |
|                                    |                                     |                          |  |   |               |  |
| Charges                            |                                     |                          | Duration   |   | Amount in INR |  |
| Internal (Institute)               |                                     |                          | 1 slot =30 min   |   | 300           |  |
| Internal (Project)                 |                                     |                          | 1 slot =30 min   |   | 360           |  |
| External (Academic/ R&D)           |                                     |                          | 1 slot =30 min   |   | 2000+ 18% GST |  |
| Industry                           |                                     |                          | 1 slot =30 min   |   | 4000+ 18% GST |  |
|                                    | *                                   | _                        | Declaration  lamaged owing to the state of t | he nature of the s                              | _             | e, the entire cost of repairing of<br>t/project/institute.                   |
| Signatur<br>Date:                  | e of the user (Stu                  | dents/I                  | RS/Project Staff):   |   |               |  |
| Name o                             | f the supervisor (i                 | n CAPIT                  | ΓAL LETTERS):  |   |               |  |
|                                    |                                     | То                       | be filled up at the  | 2D-XRD Labora                                   | tory          |  |
| Name o                             | f the Operator:                     |                          |  |   |               |  |

Signature of the Equipment Operator